BUK7540-100A N-channel TrenchMOS standard level FET Rev. 2 — 20 April 2011



Product data sheet

Product profile 1.

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

■ AEC Q101 compliant

Low conduction losses due to low on-state resistance

1.3 Applications

Automotive and general purpose power switching

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	100	V
I _D	drain current	T _{mb} = 25 °C	-	-	37	Α
P _{tot}	total power dissipation		-	-	138	W
Static cha	racteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 40 \text{ A};$ $T_j = 25 \text{ °C}$	-	30	40	mΩ
Avalanche	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 26 A; $V_{sup} \le$ 25 V; R_{GS} = 50 Ω ; V_{GS} = 5 V; $T_{j(init)}$ = 25 °C; unclamped	-	-	31	mJ



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain	mb	D
3	S	source		_G (EA)
mb	D	mounting base; connected to drain		mbb076 S
			SOT78A (TO-220AB)	

3. Ordering information

Table 3. Ordering information

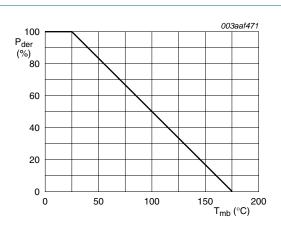
Type number	Package		
	Name	Description	Version
BUK7540-100A	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	100	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	100	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	T _{mb} = 100 °C	-	26	Α
		T _{mb} = 25 °C	-	37	Α
I _{DM}	peak drain current	T _{mb} = 25 °C; pulsed	-	149	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C	-	138	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drai	in diode				
Is	source current	T _{mb} = 25 °C	-	37	Α
I _{SM}	peak source current	pulsed; T _{mb} = 25 °C	-	149	Α
Avalanche i	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 26 A; V_{sup} ≤ 25 V; R_{GS} = 50 Ω; V_{GS} = 5 V; $T_{j(init)}$ = 25 °C; unclamped	-	31	mJ



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \,\%$$

Fig 1. Normalized total power dissipation as a function of mounting base temperature

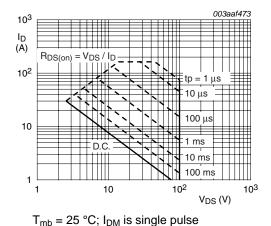
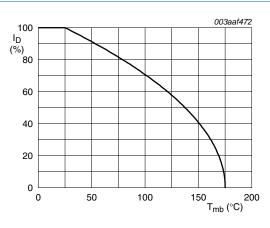


Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage



$$I_{der} = \frac{I_D}{I_{D(25C)}} \times 100\%$$

V_{GS} ≥ 10 V

Fig 2. Normalized continuous drain current as a function of mounting base temperature

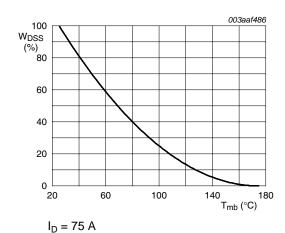
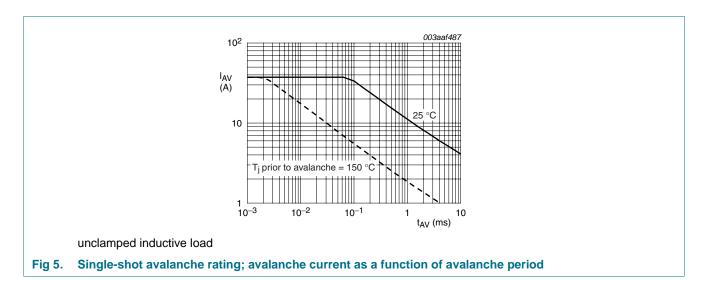


Fig 4. Normalised drain-source non-repetitive avalanche energy as a function of mounting-base temperature



5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base		-	-	1.1	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	in free air	-	60	-	K/W

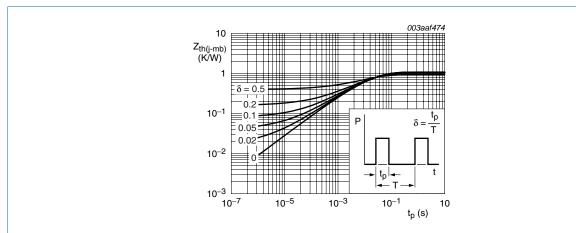


Fig 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	100	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	89	-	-	V
V _{GS(th)}	gate-source threshold	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	2	3	4	V
	voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}$	-	-	4.4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C}$	1	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
		$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μΑ
I _{GSS} gate leakage curre	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
Doon	drain-source on-state	$V_{GS} = 10 \text{ V}; I_D = 40 \text{ A}; T_j = 25 \text{ °C}$	-	30	40	mΩ
resistance		$V_{GS} = 10 \text{ V}; I_D = 40 \text{ A}; T_j = 175 \text{ °C}$	-	-	108	mΩ
Dynamic (characteristics					
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	1720	2293	pF
C _{oss}	output capacitance	T _j = 25 °C	-	216	259	pF
C _{rss}	reverse transfer capacitance		-	133	182	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 5 \text{ V};$	-	12	18	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	55	83	ns
t _{d(off)}	turn-off delay time		-	48	67	ns
t _f	fall time		-	30	42	ns
L _D	internal drain inductance	measured from contact screw on tab to centre of die; $T_j = 25$ °C	-	3.5	-	nΗ
		from drain lead 6 mm from package to centre of die; $T_j = 25$ °C	-	4.5	-	nΗ
L _S	internal source inductance	from source lead 6 mm from package to source bond pad; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ
Source-dr	ain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.85	1.2	V
		$I_S = 37 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	1.1	-	V
t _{rr}	reverse recovery time	$I_S = 37 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$;	-	70	-	ns
Q _r	recovered charge	$V_{GS} = -10 \text{ V}; V_{DS} = 30 \text{ V}; T_j = 25 \text{ °C}$	-	0.24	-	μC

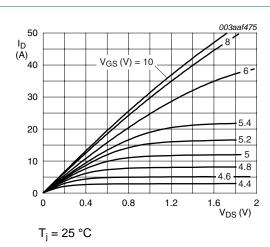


Fig 7. Output characteristics: drain current as a function of drain-source voltage; typical values

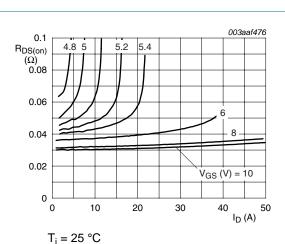


Fig 8. Drain-source on-state resistance as a function of drain current; typical values

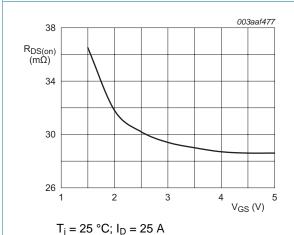


Fig 9. Drain-source on-state resistance as a function of gate-source voltage; typical values

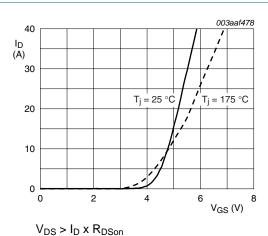


Fig 10. Transfer characteristics: drain current as a function of gate-source voltage; typical values

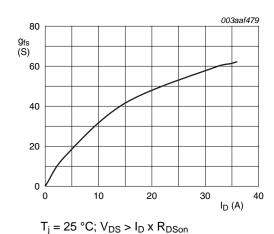
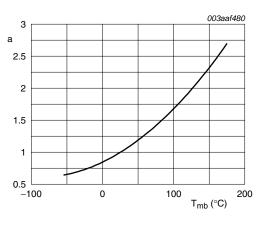


Fig 11. Forward transconductance as a function of drain current; typical values



 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$

Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature

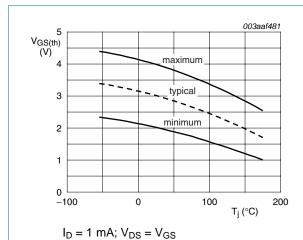
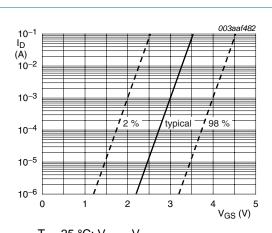


Fig 13. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25 \,^{\circ}\text{C}; \, V_{DS} = V_{GS}$

Fig 14. Sub-threshold drain current as a function of gate-source voltage

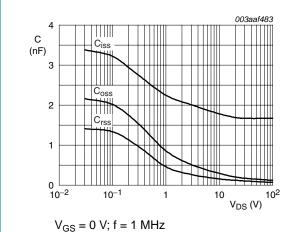


Fig 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

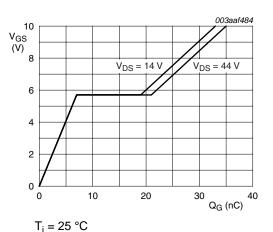
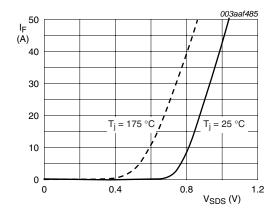


Fig 16. Gate-source voltage as a function of gate charge; typical values



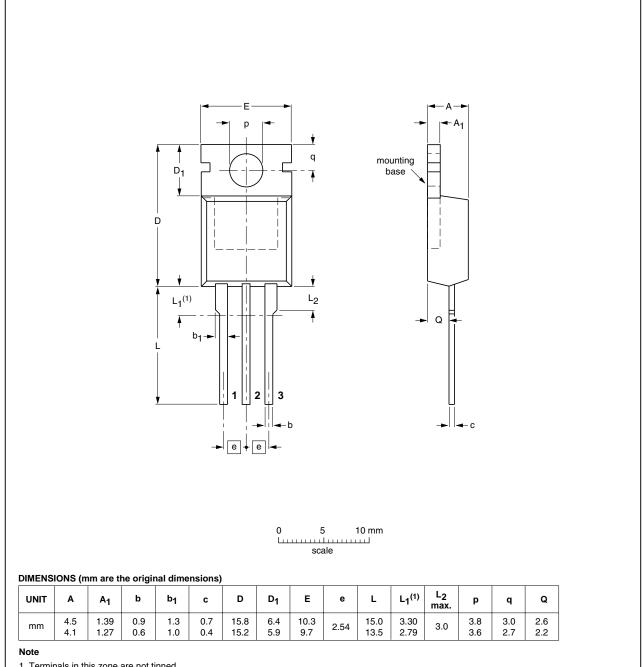
 $V_{GS} = 0 V$

Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB

SOT78A



1. Terminals in this zone are not tinned.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT78A		3-lead TO-220AB	SC-46		03-01-22 05-03-14

Fig 18. Package outline SOT78A (TO-220AB)

BUK7540-100A

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
BUK7540-100A v.2	20110420	Product data sheet	-	BUK7540-100A_1	
Modifications:		The format of this data sheet has been redesigned to comply with the new identity guidelir of NXP Semiconductors.			
	 Legal texts ha 	ve been adapted to the new	company name where	appropriate.	
BUK7540-100A_1	19991201	Product specification	-	-	

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9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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